		STUDY MODULE D	ESCRIPTION FORM		
	of the module/subject ntum Metrology		Code 1010803111010832686		
Field of study			Profile of study (general academic, practical	Year /Semester	
Communications Technologies			general academic	,	
Elective path/specialty			Subject offered in: English	Course (compulsory, elective) elective	
Cycle o	f study:		Form of study (full-time,part-time))	
	Doctora	al studies	full-time		
No. of I	nours		No. of credits		
Lectu	re: 15 Classes	s: - Laboratory: -	Project/seminars:	- 2	
Status	=	program (Basic, major, other)	(university-wide, from another	,	
		major	fr	om field	
Educat	ion areas and fields of sci	ence and art		ECTS distribution (number and %)	
tech	nical sciences			2 100%	
pro em tel. Ele	f. dr hab. inż. Waldema ail: nawrocki@et.put.pu 61665 3888 ctronics and Telecomm anka 3	ar Nawrocki oznan.pl			
Prer	equisites in term	s of knowledge, skills an	d social competencies	•	
1	Knowledge	 Student has a systematic knowledge of physics, in particular of solid-state physics. Sydent has a basic knowledge of electronics and metrology 			
	Skills	, 3			
2		1. Is able to extract information from Polish or English language literature, databases and other sources. Is able to synthesize gathered information, draw conclusions, and justify opinions.			
		2. Is capable of studying autonomously.			
		3. Demonstrates the ability to so		(=)	
3	Social competencies	1. Is aware of the limitations of h self-study.	C C	skills; is committed to further	
Assı	Imptions and obi	2. Is able to participate in collabored ectives of the course:	brative projects. (
-To pr introdu	esent of the basic defir uce students to the ana cal carrying out laborat	nitions and concepts of metrology, alysis and presentation of data and ory experiments involving the pre mes and reference to the	d the determination of errors an paration and execution of mea	nd measurement uncertainty. surements.	
Knov	vledge:				
1. Ph metrol syster	S student has a system ogy, which is necessa ns components. Has k	natic knowledge, together with ner ry to measure the signal properties nowledge of measurement method	s and the parameters of electro ds, measurement equipment	onic and telecommunication	
2. Has		of units and standards - [SD_W02	2]		
1. Ph	student Is able to ext	ract information from Polish or Engination, draw conclusions, and jus		bases and other sources. Is able	
-	0	ocumented study, in English or in	,	metrology - [SD_U02]	
		onomously [SD_U03]			
		for scientific analyses - [SD_U04]			
		is of research and to prpare a scie	entific report (paper) - [SD_00	6]	
	al competencies:		rapagrah ICD K041		
		I self critical to results of scientific	• = •		
2. is a		enges facing metrology and syster	ns or units in the 2 ist century.		

Assessment methods of st	udy outcomes	
-Lectures passing based on written test from content of the lectures.		
Course descript	ion	
- Basic definitions and terms of metrology, in particular of quantum metro	ology.	
- Systems of units: history, standards of units, system uf units now (SI s	ystem) and in the future - pro	posals.
- Quantum system of units		
 Quantum metrological triangle and quantum metrological pyramid. 		
- Basic terms in quantum metrology, Heisengerg's uncertaonty principle		olution.
- Superconductivity. Josephson effect and its applications in metrology (voltage standards	
- Zjawisko Josephsona.		
- Direct current voltage standards.b SAet-up of voltage standards in Wa	rsaw.	
 SQUID detectors and their applications. Calsical and quantum Hall effect. Electrical resistance standard using a 	nuantum Hall offect	
- Quantization of electrical conductance in nanostructures.	quantum nai eneci.	
- Single electron tunneling and a direct current standard.		
- Scanning probe microscopy fpr nanoscience and nano technology.		
- Frequency standards and atomic clocks. International Time Scale.		
- Optical interefrometry for lenght standards.		
- Quantum standards of a mass.		
- Scale of temperature based on the Boltzmann constant.		
- Low noise preamplifiers.		
Basic bibliography:		
1. Wstęp do metrologii kwantowej, Nawrocki W., Wydawnictwo PP, Poz	nań 2007	
2. Quantenmasse in der elektrischen Messtechnik, Kose V., Melchert F.	, WVH Verlag, Weinheim - N	lew York, 1991.
 Analiza danych w naukach ścisłych i technice, Zięba A., Wydawnictwick 	o Naukowe PWN, Warszawa	a 2013
Additional bibliography:		
1. Systemy mikroskopii bliskich oddziaływań w badaniach mikro- i nanos Wrocławskiej, Wrocław 2004	struktur, Gotszalk T.P., Oficy	na Wyd. Politechniki
2. Wzorcowanie aparatury pomiarowej, Piotrowski J., Kostyrko K., Wyd		
Practical Data Acquisition for Instromentation and Control Systems, P	Park J. Mackey S., Elsevier, 2	2003
Result of average studen	t's workload	
Activity		Time (working hours)
1. Participation in lectures and discussions	20	
2. Preparation for exam		10
Student's worklo	bad	
Source of workload	hours	ECTS
Total workload	30	2
Contact hours	20	2
Practical activities	0	0